

<b>Notice of References Cited</b>	Application/Control No. 10/827,457	Applicant(s)/Patent Under Reexamination MAEKAWA ET AL.	
	Examiner Marianne L. Padgett	Art Unit 1762	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0152329 A1	08-2004	Di Dio, Luigi	438/710
*	B	US-6,228,435 B1	05-2001	Yoshikawa et al.	427/489
*	C	US-6,764,812 B1	07-2004	Kubacki, Ronald M.	430/322
*	D	US-2002/0014470	02-2002	Okada et al.	216/24
*	E	US-6,878,419 B2	04-2005	David et al.	427/535
*	F	US-6,784,459 B2	08-2004	Seki et al.	257/88
*	G	US-2006/0169672 A1	08-2006	Toyoda, Naoyuki	216/067
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0989778 A1	03-2000	European	Seki et al.	H05B 1/00
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

11/3/06